

# Search Notes



Application/Control No.

10/691,705

Examiner

Sara W. Crane

Applicant(s)/Patent under  
Reexamination

HIRAMOTO, AKI

Art Unit

2811

## SEARCHED

Class	Subclass	Date	Examiner
257	98 99 100	3/05	SWC
313	501 512		
362	311 800		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

EAST	DATE	EXMR
chip and lens and (resin with expand) also	305	SWC
and (resin same space same expand)		